

YK080N04-D3

N-Channel Enhancement Mode Field Effect Transistor



康比電子
HORNBY ELECTRONIC

General Description

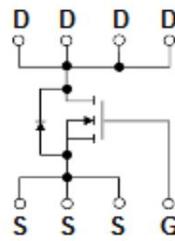
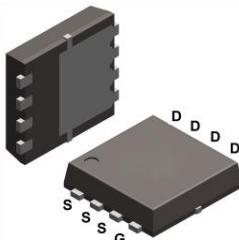
The YK080N04-D3 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications.

Application

- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply

Features

- $V_{DS} = 40V, I_D = 40A$
- $R_{DS(ON)} < 8m\Omega @ V_{GS}=4.5V$
- $R_{DS(ON)} < 10m\Omega @ V_{GS}=10V$
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation
- Special process technology for high ESD capability



Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
080N04	YK080N04-D3	PDFN3×3-8L	5000 pcs / Tape & Reel

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DSS}	40	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current-Continuous $V_{GS}=4.5V$, @ $T_a=25^\circ C$	I_D	40	A
Pulsed Drain Current(Note 2)	I_{DM}	120	A
Maximum Power Dissipation @ $T_a=25^\circ C$	P_D	25	W
Single pulse avalanche energy (Note 3)	EAS	78	mJ
Operating Junction and Storage Temperature Range	T_J	-55 ~ +150	°C

Thermal Characteristics

Thermal Resistance Junction-to-Case (Note 1)	$R_{\theta JC}$	5	°C/W
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Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 250\mu\text{A}$	40		-	V
Zero Gate Voltage Drain Current	I_{DSS}	$\text{V}_{\text{DS}} = 32\text{V}, \text{V}_{\text{GS}} = 0\text{V}$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$\text{V}_{\text{GS}} = \pm 20\text{V}, \text{V}_{\text{DS}} = 0\text{V}$	-	-	± 100	nA
On Characteristics						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_{\text{DS}} = 250\mu\text{A}$	1.2	-	2.5	V
Drain-Source On-State Resistance (NOT2)	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}} = 4.5\text{V}, \text{I}_{\text{DS}} = 10\text{A}$	-	-	10	$\text{m}\Omega$
		$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_{\text{DS}} = 12\text{A}$	-	-	8	
Dynamic Characteristics						
Input Capacitance	C_{iss}	$\text{V}_{\text{GS}} = 0\text{V}$ $\text{V}_{\text{DS}} = 15\text{V}$ $f = 1.0\text{MHz}$	-	2330	-	pF
Output Capacitance	C_{oss}		-	195	-	
Reverse Transfer Capacitance	C_{rss}		-	138	-	
Switching Characteristics						
Turn-on Delay Time	$\text{T}_{\text{d(on)}}$	$\text{VDD} = 15\text{V}$ $\text{VGS} = 10\text{V}$ $\text{RG} = 3.3\Omega$ $\text{ID} = 1\text{A}$	-	14.3	-	ns
Turn-on Rise Time	T_r		-	2.6	-	
Turn-Off Delay Time	$\text{T}_{\text{d(OFF)}}$		-	77	-	
Turn-Off Fall Time	T_f		-	4.8	-	
Total Gate Charge	Q_g	$\text{VDD} = 20\text{V}$ $\text{VGS} = 4.5\text{V}$ $\text{ID} = 20\text{A}$	-	18.8	-	nC
Gate-Source Charge	Q_{gs}		-	4.7	-	
Gate-Drain Charge	Q_{gd}		-	8.2	-	
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 2)	V_{SD}	$\text{I}_{\text{SD}} = 1\text{A}, \text{VGS} = 0\text{V},$ $= 25^\circ\text{C}$	T_j	-	-	1.2
Diode Forward Current (Note 1、4)	I_s		-	-	70	A

Notes:

- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper
- The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- The EAS data shows Max. rating. The test condition is $\text{VDD} = 25\text{V}, \text{VGS} = 10\text{V}, \text{L} = 0.5\text{mH}$
- The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation

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Typical Electrical and Thermal Characteristics

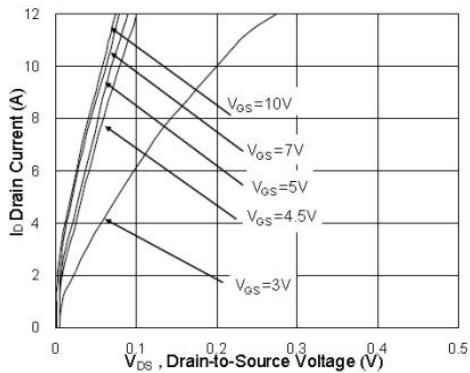


Fig 1 Typical Output Characteristics

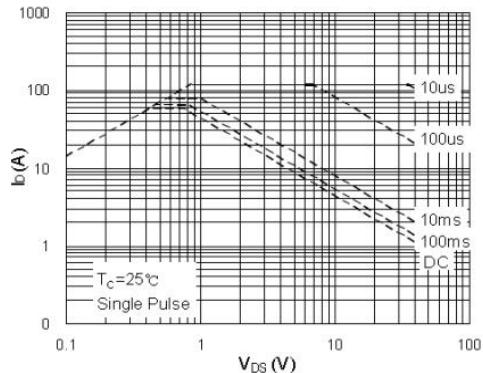


Fig 2 Maximum Safe Operating Area

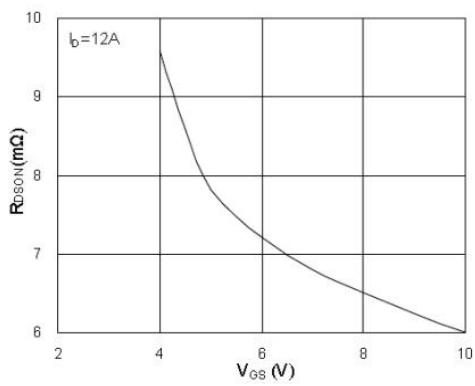


Fig 3 On-Resistance vs. Gate-Source Voltage

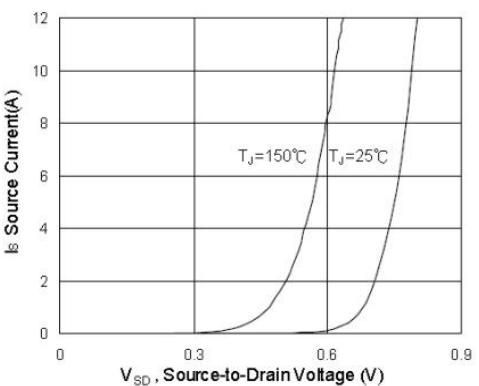


Fig 4 Body-Diode Characteristics

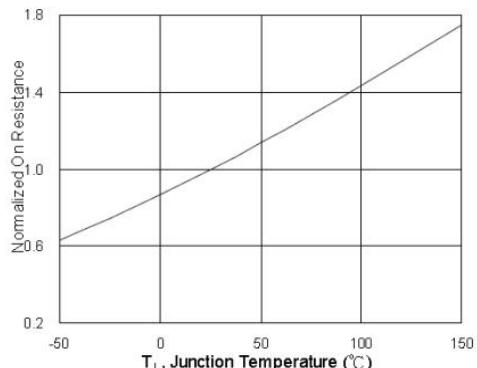


Fig 5 On-Resistance vs. Junction Temperature

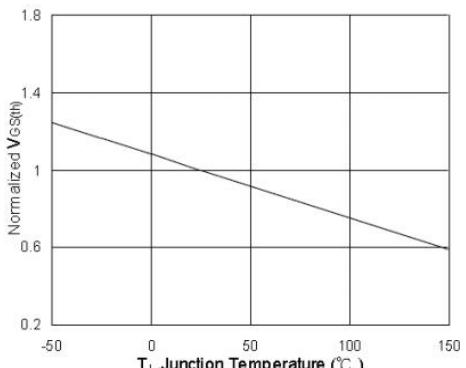


Fig 6 Gate Threshold Voltage
vs. Junction Temperature

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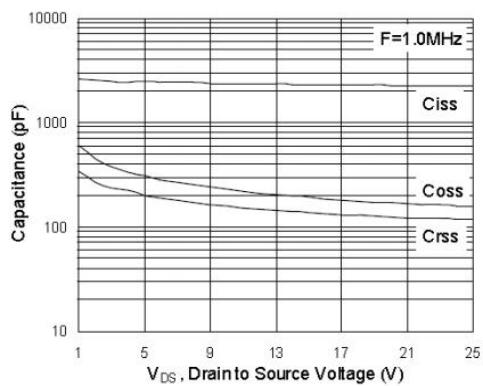


Fig 7 Capacitance Characteristics

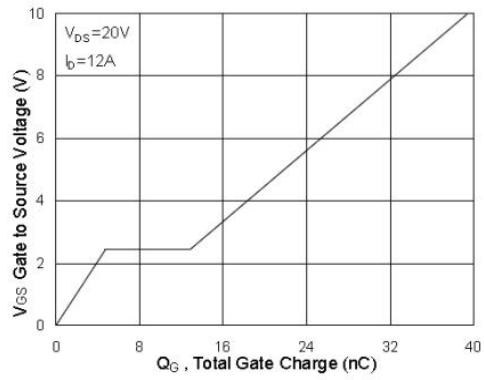


Fig 8 Gate-Charge Characteristics

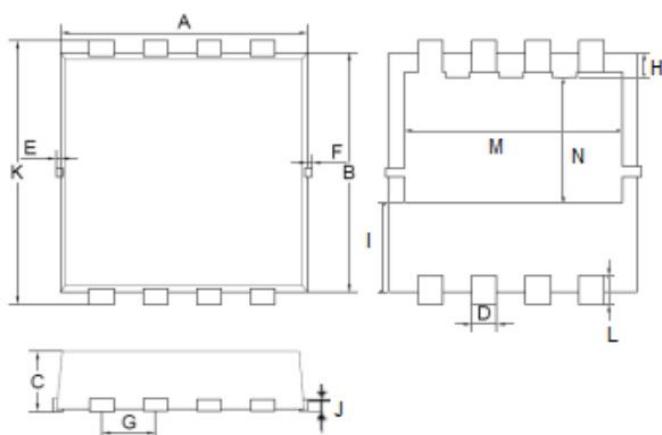
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PDFN3*3-8L Package Information



PDFN3×3-8L		
Dimension	Min.	Max.
A	2.90	3.10
B	2.90	3.10
C	0.65	0.85
D	0.20	0.40
E	0.00	0.10
F	0.00	0.10
G	0.55	0.75
H	0.20	0.40
I	0.70	1.10
J	0.10	0.20
K	3.15	3.45
L	0.20	0.40
M	2.35	2.55
N	1.500	1.900

